Product/Process Change Notice - PCN 21_0182 Rev. -

Analog Devices, Inc. One Analog Way, Wilmington, MA 01887

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

PCN Title: Addition of alternative Fab foundry and die revision for ADBMS1818

Publication Date: 31-Aug-2021

Effectivity Date: 03-Dec-2021 *(the earliest date that a customer could expect to receive changed material)*

Revision Description:
Initial Release

Description Of Change:

ADI is adding Tower Jazz, Japan (Fab 5) as an alternate Fab foundry to Tower Jazz, Israel (Fab 2) for ADBMS1818. In addition, the 1st epi layer will be removed from the device.

Reason For Change:

The use of the alternative Fab foundry will ensure a continued source of product supply and to increase capacity.
The removal of the 1st epi layer that is used in addition to the standard epi layer will improve Fab throughput and quality.

Impact of the change (positive or negative) on fit, form, function & reliability:

There is no impact on the form, fit, function and reliability of the devices.

Product Identification *(this section will describe how to identify the changed material)*

Date Code and Lot number will be used for product identification.

Summary of Supporting Information:

Qualification will be performed per Industry Standard Test Methods. See attached Qualification Plan.

Supporting Documents

Attachment 1: Type: Qualification Plan

ADI_PCN_21_0182_Rev_-_Qualification Plan Summary for ADBMS1818 at Tower Jazz Japan.pdf

Attachment 2: Type: Qualification Results Summary

ADI_PCN_21_0182_Rev_-_Qualification Results Summary for ADBMS1818 Removal of the 1st Epi Layer.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.			
Americas: PCN_Americas@analog.com	**Europe:** PCN_Europe@analog.com	**Japan:** PCN_Japan@analog.com	**Rest of Asia:** PCN_ROA@analog.com

Appendix A - Affected ADI Models				
Added Parts On This Revision - Product Family / Model Number (6)				
ADBMS1818 / ADBMS1818ASWAZ	ADBMS1818 / ADBMS1818ASWAZ-R7	ADBMS1818 / ADBMS1818ASWAZ-RL	ADBMS1818 / ADBMS1818ASWZ	ADBMS1818 / ADBMS1818ASWZ-R7
ADBMS1818 / ADBMS1818ASWZ-RL				

Appendix B - Revision History			
Rev	**Publish Date**	**Effectivity Date**	**Rev Description**
Rev. -	31-Aug-2021	03-Dec-2021	Initial Release

Qualification Plan Summary for ADBMS1818 at Tower Jazz Japan

QUALIFICATION PLAN			
TEST	**SPECIFICATION**	**SAMPLE SIZE**	**EXPECTED COMPLETION DATE**
Electrostatic Discharge *Human Body Model*	JEDEC *JESD22-A114*	3/voltage	Jan 2022
Electrostatic Discharge *Field-Induced Charged Device Model*	JEDEC *JS-002*	3/voltage	Jan 2022
Latch-Up	JEDEC *JESD78*	6	Jan 2022
Highly Accelerated Stress Test (HAST)*	JEDEC *JESD22-A110*	3 x 45	Jan 2022
Unbiased Highly Accelerated Stress Test (UHAST) *	JEDEC *JESD22-A118*	3 x 45	Jan 2022
High Temperature Operating Life (HTOL)*	JEDEC *JESD22-A108*	3 x 45	Jan 2022
Temperature Cycle (TC)*	JEDEC *JESD22-A104*	3 x 45	Jan 2022
High Temperature Storage Life (HTSL)	JEDEC *JESD22-A103*	1 x 45	Jan 2022

*Preconditioned per JEDEC/IPC J-STD-020

Qualification Results Summary of ADBMS1818 Removal of the 1st Epi Layer			
TEST	CONDITIONS	SAMPLE SIZE	RESULTS
Highly Accelerated Stress Test (HAST)*	**JEDEC** JESD22-A110	**3x45**	**PASS**
High Temperature Operating Life (HTOL)*	**JEDEC** JESD22-A108	**3x45**	**PASS**
Temperature Cycle (TC)*	**JEDEC** JESD22-A104	**3x45**	**PASS**
Autoclave (PCT) *	**JEDEC** JESD22-A102	**3x45**	**PASS**
High Temperature Storage Life (HTSL)	**JEDEC** JESD22-A103	**1x45**	**PASS**
FICDM	**JEDEC** JS-002	**3/voltage**	**PASS**
HBM	**ESDA/JEDEC** JS-001-2011	**3/voltage**	**PASS**
LU	**JEDEC** JESD78	**6**	**PASS**

*Preconditioned per JEDEC/IPC J-STD-020